Supplementary figures (abstract #894)

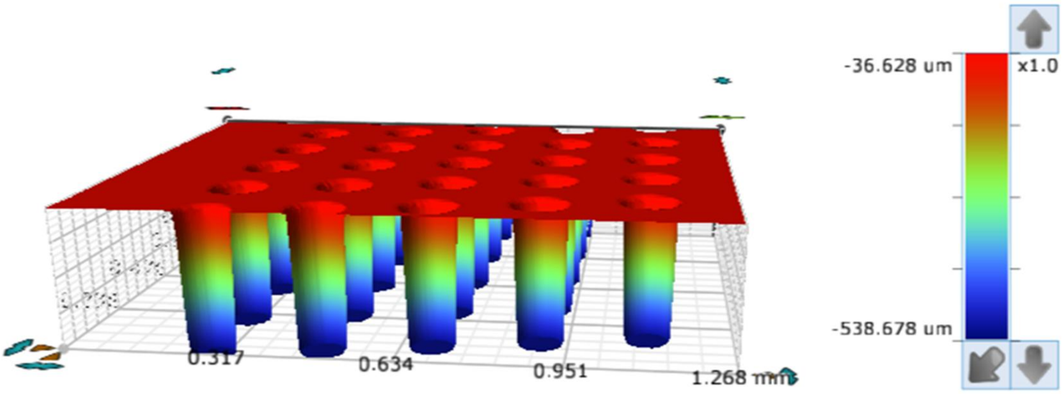

Figure 1. Optical profilometer scan of etched TSVs.

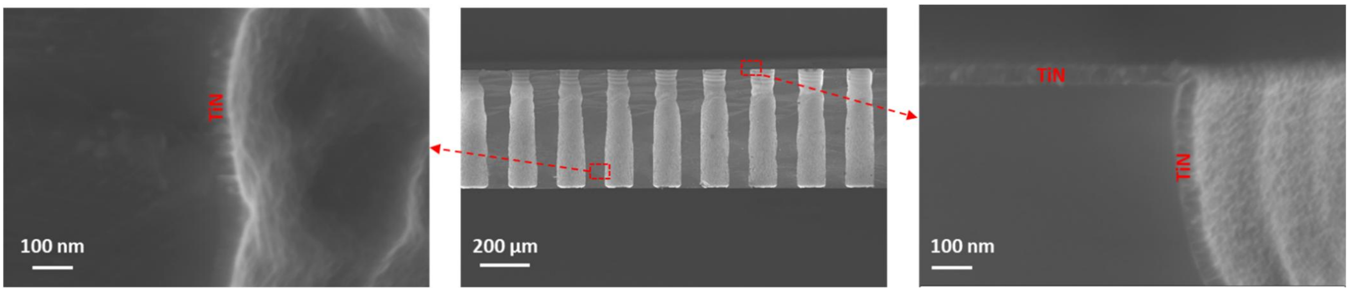

Figure 2. Scanning electron micrographs of TiN coating inside TSVs.

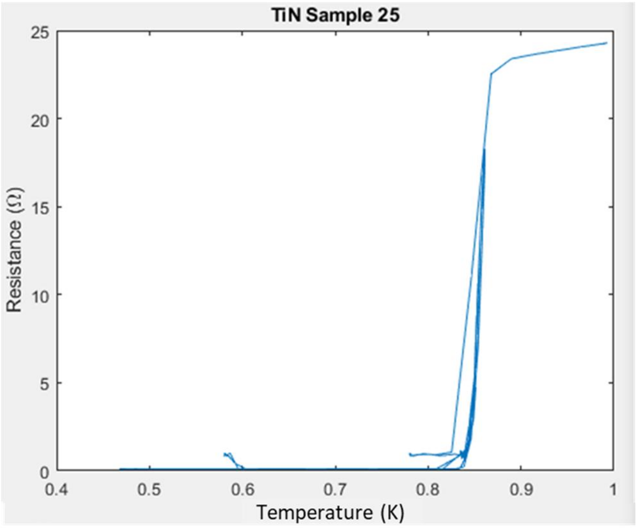

Figure 3. Resistance of an ensemble of TiN coated TSVs as a function of temperature.